## Onsemi

### ECOSPARK<sup>®</sup>2 300 mJ, 400 V, **N-Channel Ignition IGBT**

### FGB3040G2-F085, FGD3040G2-F085, FGP3040G2-F085, FGI3040G2-F085

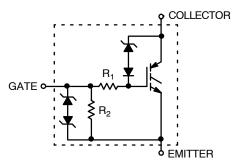
#### Features

- SCIS Energy = 300 mJ at  $T_I = 25^{\circ}C$
- Logic Level Gate Drive
- AEC-Q101 Qualified and PPAP Capable
- These Devices are Pb-Free and are RoHS Compliant

#### Applications

- Automotive Ignition Coil Driver Circuits
- Coil On Plug Applications

#### SYMBOL



COLLECTOR G (FLANGE) Е JEDEC TO-263AB D<sup>2</sup>PAK-3 (TO-263, 3-LEAD) CASE 418AJ COLLECTOR G (FLANGE) Е JEDEC TO-263AA DPAK3 (TO-252 3 LD) CASE 369AS E<sub>C</sub>G <sup>E</sup>c<sub>G</sub> JEDEC TO-262AA JEDEC TO-220AB TO-220-3LD I2PAK (TO-262 3 LD) CASE 340AT CASE 418AV MARKING DIAGRAMS \$Y&Z&3&K \$Y&Z&3&K FGB FGD 3040G2 3040G2 \$Y&Z&3&K FGI \$Y&Z&3&K 3040G2 FGP  $\mathbf{C}$ 3040G2

FGx3040G2 = Specific Device Code (x = B/D/P/I) \$Y

= onsemi Logo

&Z

&З

- = Assembly Plant Code
- = 3-Digit Date Code
- &K = 2-Digits Lot Run Traceability Code

#### **ORDERING INFORMATION**

See detailed ordering and shipping information on page 8 of this data sheet.

Symbol	Parameter	Rating	Unit
BV <sub>CER</sub>	Collector to Emitter Breakdown Voltage (I <sub>C</sub> = 1 mA)	400	V
BV <sub>ECS</sub>	Emitter to Collector Voltage – Reverse Battery Condition ( $I_C = 10 \text{ mA}$ )	28	V
E <sub>SCIS25</sub>	Self Clamping Inductive Switching Energy (Note 1)	300	mJ
E <sub>SCIS150</sub>	Self Clamping Inductive Switching Energy (Note 2)	170	mJ
I <sub>C25</sub>	Collector Current Continuous, at V <sub>GE</sub> = 5.0 V, $T_C$ = 25°C	41	А
I <sub>C110</sub>	Collector Current Continuous, at $V_{GE}$ = 5.0 V, $T_C$ = 110°C	25.6	А
$V_{\text{GEM}}$	Gate to Emitter Voltage Continuous	±10	V
P <sub>D</sub>	Power Dissipation Total, at $T_C = 25^{\circ}C$	150	W
	Power Dissipation Derating, for $T_C > 25^{\circ}C$	1	W/°C
TJ	Operating Junction Temperature Range	–55 to +175	°C
T <sub>STG</sub>	Storage Junction Temperature Range	–55 to +175	°C
ΤL	Max. Lead Temp. for Soldering (Leads at 1.6 mm from case for 10 s)	300	°C
T <sub>PKG</sub>	Reflow Soldering according to JESD020C	260	°C
ESD	HBM-Electrostatic Discharge Voltage at 100 pF, 1500 $\Omega$	4	kV
	CDM-Electrostatic Discharge Voltage at 1 $\Omega$	2	kV

#### DEVICE MAXIMUM RATINGS (T<sub>A</sub> = 25°C unless otherwise noted)

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality

should not be assumed, damage may occur and reliability may be affected. 1. Self Clamping Inductive Switching Energy ( $E_{SCIS25}$ ) of 300 mJ is based on the test conditions that starting Tj = 25°C; L = 3 mHy,  $I_{SCIS}$  = 14.2 A,  $V_{CC}$  = 100 V during inductor charging and  $V_{CC}$  = 0 V during the time in clamp. 2. Self Clamping Inductive Switching Energy ( $E_{SCIS150}$ ) of 170 mJ is based on the test conditions that starting Tj = 150°C; L = 3 mHy,  $I_{SCIS}$  = 10.8 A,  $V_{CC}$  = 100 V during inductor charging and  $V_{CC}$  = 0 V during the time in clamp.

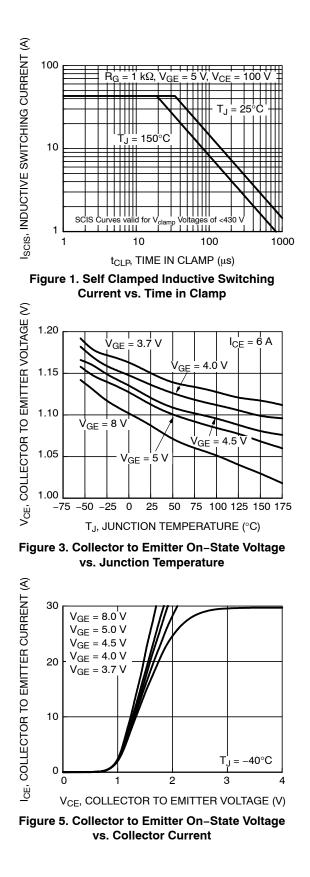
Symbol	Parameter	Test Condition	าร	Min	Тур	Max	Unit
OFF STATI	E CHARACTERISTICS						
BV <sub>CER</sub>	Collector to Emitter Breakdown Voltage	$I_{CE}$ = 2 mA, $V_{GE}$ = 0, $R_{GE}$ = 1 kΩ, $T_{J}$ = -40 to 150°C		370	400	430	V
BV <sub>CES</sub>	Collector to Emitter Breakdown Voltage	$I_{CE}$ = 10 mA, $V_{GE}$ = 0 V, $R_{GE}$ = 0, T <sub>J</sub> = -40 to 150°C		390	420	450	V
BV <sub>ECS</sub>	Emitter to Collector Breakdown Voltage	$I_{CE} = -20 \text{ mA}, V_{GE} = 0 \text{ V}, T_{J} = 25^{\circ}\text{C}$		28	-	-	V
$BV_{GES}$	Gate to Emitter Breakdown Voltage	I <sub>GES</sub> = ±2 mA		±12	±14	-	V
I <sub>CER</sub>	Collector to Emitter Leakage Current	$V_{CE}$ = 250 V, $R_{GE}$ = 1 k $\Omega$	$T_J = 25^{\circ}C$	-	-	25	μA
			T <sub>J</sub> = 150°C	-	-	1	mA
I <sub>ECS</sub>	Emitter to Collector Leakage Current	V <sub>EC</sub> = 24 V	$T_J = 25^{\circ}C$	-	-	1	mA
			T <sub>J</sub> = 150°C	-	-	40	1
R <sub>1</sub>	Series Gate Resistance			-	120	_	Ω
R <sub>2</sub>	Gate to Emitter Resistance			10K	-	30K	Ω
ON STATE	CHARACTERISTICS					-	-
V <sub>CE(SAT)</sub>	Collector to Emitter Saturation Voltage	$I_{CE}$ = 6 A, $V_{GE}$ = 4 V	$T_J = 25^{\circ}C$	-	1.15	1.25	V
V <sub>CE(SAT)</sub>	Collector to Emitter Saturation Voltage	$I_{CE}$ = 10 A, $V_{GE}$ = 4.5 V	T <sub>J</sub> = 150°C	-	1.35	1.50	V
V <sub>CE(SAT)</sub>	Collector to Emitter Saturation Voltage	$I_{CE}$ = 15 A, $V_{GE}$ = 4.5 V	T <sub>J</sub> = 150°C	-	1.68	1.85	V
E <sub>SCIS</sub>	Self Clamped Inductive Switching	$\label{eq:L} \begin{array}{l} L=3.0 \text{ mHy}, \text{ RG}=1  \text{k}\Omega, \\ \text{VGE}=5 \text{ V}, \text{ (Note 3)} \end{array}$	TJ = 25°C	-	-	300	mJ
DYNAMIC	CHARACTERISTICS						
Q <sub>G(ON)</sub>	Gate Charge	$I_{CE}$ = 10 A, $V_{CE}$ = 12 V, $V_{GE}$ = 5 V		-	21	-	nC
V <sub>GE(TH)</sub>	Gate to Emitter Threshold Voltage	$I_{CE}$ = 1 mA, $V_{CE}$ = $V_{GE}$	$T_J = 25^{\circ}C$	1.3	1.7	2.2	V
			T <sub>J</sub> = 150°C	0.75	1.2	1.8	
$V_{GEP}$	Gate to Emitter Plateau Voltage	$V_{CE}$ = 12 V, $I_{CE}$ = 10 A		_	2.8	_	V
SWITCHIN	G CHARACTERISTICS						
t <sub>d(ON)R</sub>	Current Turn-On Delay Time-Resistive	$V_{CE} = 14 \text{ V}, \text{ R}_{L} = 1 \text{ k}\Omega$		-	0.9	4	μs
t <sub>rR</sub>	Current Rise Time-Resistive	$V_{GE}$ = 5 V, $R_G$ = 1 k $\Omega$ , T <sub>J</sub> = 25°C		-	1.9	7	μs
t <sub>d(OFF)L</sub>	Current Turn-Off Delay Time-Inductive	$V_{CE} = 300 \text{ V, } L = 1 \text{ mH}, \\ V_{GE} = 5 \text{ V, } R_G = 1 \text{ k}\Omega, \\ I_{CE} = 6.5 \text{ A, } T_J = 25^{\circ}\text{C}$		-	4.8	15	μs
t <sub>fL</sub>	Current Fall Time-Inductive			-	2.0	15	μs
HERMAL	CHARACTERISTICS	•					-
$R_{\theta JC}$	Thermal Resistance Junction to Case			_	-	1	°C/M

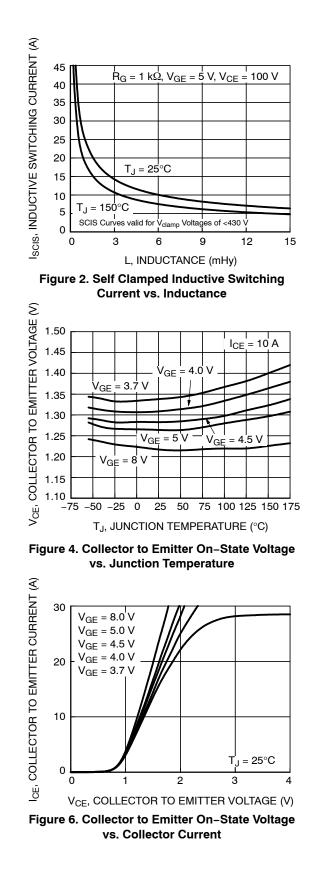
#### ELECTRICAL CHARACTERISTICS (T1 = 25°C unless otherwise noted)

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product

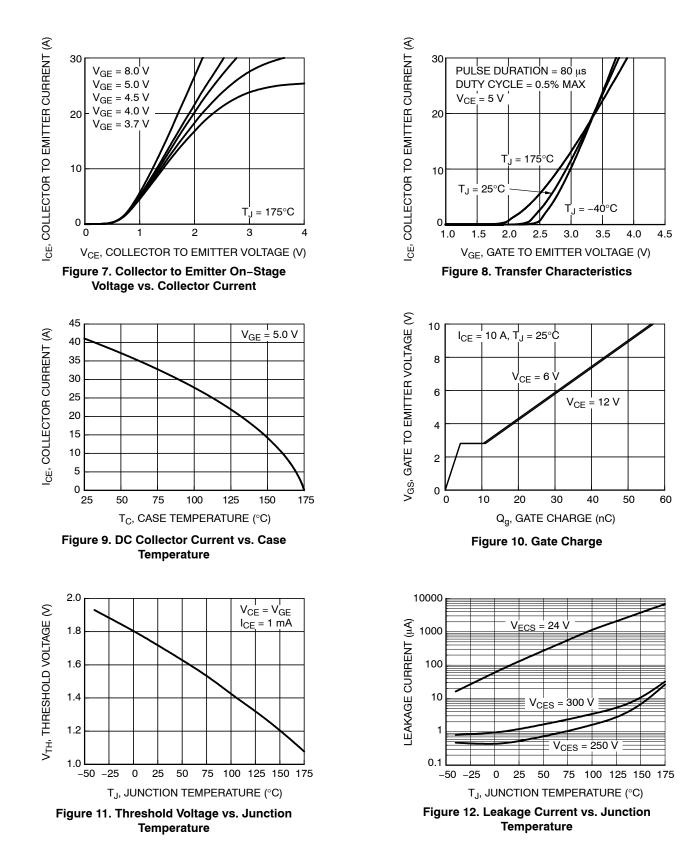
performance may not be indicated by the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions. 3. Self Clamping Inductive Switching Energy ( $E_{SCIS25}$ ) of 300 mJ is based on the test conditions that starting Tj = 25°C; L = 3 mHy,  $I_{SCIS}$  = 14.2 A,  $V_{CC}$  = 100 V during inductor charging and  $V_{CC}$  = 0 V during the time in clamp.

#### **TYPICAL PERFORMANCE CURVES**





TYPICAL PERFORMANCE CURVES (Continued)



#### 2000 12 f = 1 MHz $I_{CE}$ = 6.5 A, $V_{GE}$ = 5 V, $R_{G}$ = 1 k $\Omega$ $V_{GE} = 0 V$ 10 Resistive t<sub>OFF</sub> SWITCHING TIME (µs) 1600 CAPACITANCE (pF) 8 Inductive t<sub>OFF</sub> 1200 CIES 6 800 4 400 CRES 2 Resistive t<sub>ON</sub> COES 0 0 75 125 50 100 150 175 20 25 10 15 25 0 5 T<sub>J</sub>, JUNCTION TEMPERATURE (°C) V<sub>DS</sub>, DRAIN TO SOURCE VOLTAGE (V) Figure 13. Switching Time vs. Junction Figure 14. Capacitance vs. Collector to Temperature **Emitter Voltage** 430 BV<sub>CER</sub>, BREAKDOWN VOLTAGE (V) 420 $I_{CER} = 10 \text{ mA}$ 410 40 [] = 25°C 400 |/| | 175°C ΤJ = 390 380 10 100 1000 6000 R<sub>G</sub>, SERIES GATE RESISTANCE (Ω) Figure 15. Breakdown Voltage vs. Series Gate Resistance 2 - DESCENDING ORDER DUTY CYCLE Z<sub>0JC</sub>, NORMALIZED THERMAL IMPEDANCE 1 D = 0.5 0.20 0.10 0.1 0.0 0.01 SINGLE PULSE

TYPICAL PERFORMANCE CURVES (Continued)

Figure 16. IGBT Normalized Transient Thermal Impedance, Junction to Case

10<sup>-2</sup>

t, RECTANGULAR PULSE DURATION (s)

10<sup>-1</sup>

1

10

10<sup>-3</sup>

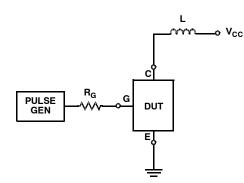
10<sup>-4</sup>

\*Operation in this area is permitted 100 during SCIS **Pulse Operation** Operation in this area is limited by Vce(on) or transconductance 10us  $I_{\rm CE},$  Collector to emitter cirrent (A) 10 De Dissibation United 100us 1 1ms 10ms \*For Single Non Repetitive Pulse operation DC & Tj=175°C Tc=25°C 100ms Vge=5.0V Rev. 2.1 0.1 10 100 500 1 V<sub>CE</sub>, COLLECTOR TO EMITTER VOLTAGE (V)

TYPICAL PERFORMANCE CURVES (Continued)

Figure 17. Forward Safe Operating Area

#### **TEST CIRCUIT AND WAVEFORMS**



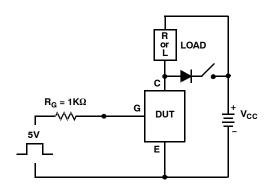


Figure 19. t<sub>ON</sub> and t<sub>OFF</sub> Switching Test Circuit

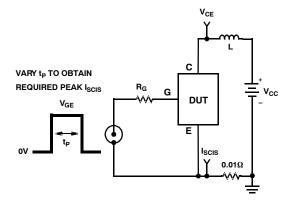
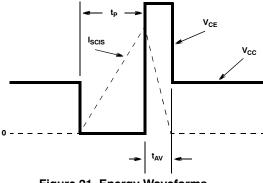
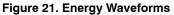


Figure 18. Inductive Switching Test Circuit

Figure 20. Energy Test Circuit



**BV<sub>CES</sub>** 



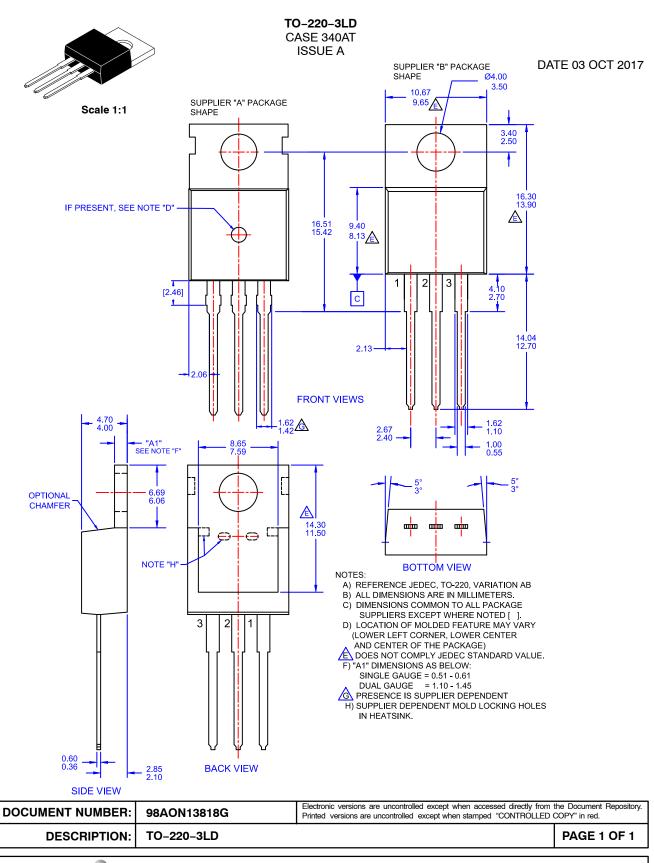
#### PACKAGE MARKING AND ORDERING INFORMATION

Device	Device Marking	Package	Shipping <sup>†</sup>
FGB3040G2-F085	FGB3040G2	D <sup>2</sup> PAK–3 (TO–263, 3–LEAD) (TO–263AB) (Pb–Free)	800 / Tape & Reel
FGD3040G2-F085	FGD3040G2	DPAK3 (TO-252 3 LD) (TO-252AA) (Pb-Free)	2500 / Tape & Reel
FGP3040G2-F085	FGP3040G2	TO-220-3LD (TO-220AB) (Pb-Free)	400 / Tube
FGI3040G2-F085	FGI3040G2	I2PAK (TO-262 3 LD) (TO-262AA) (Pb-Free)	400 / Tube

+For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

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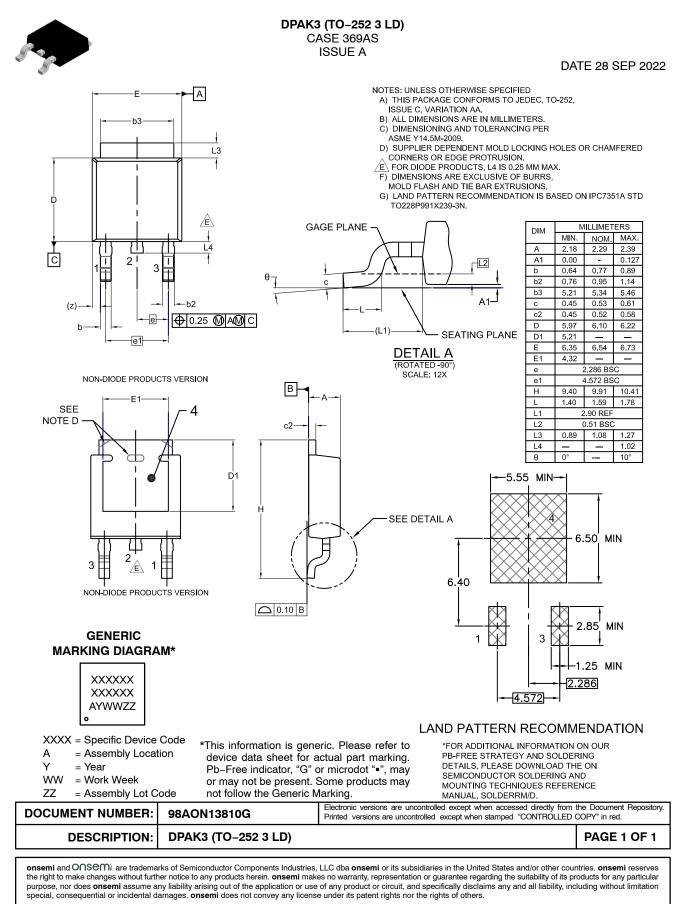




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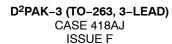
#### MECHANICAL CASE OUTLINE PACKAGE DIMENSIONS

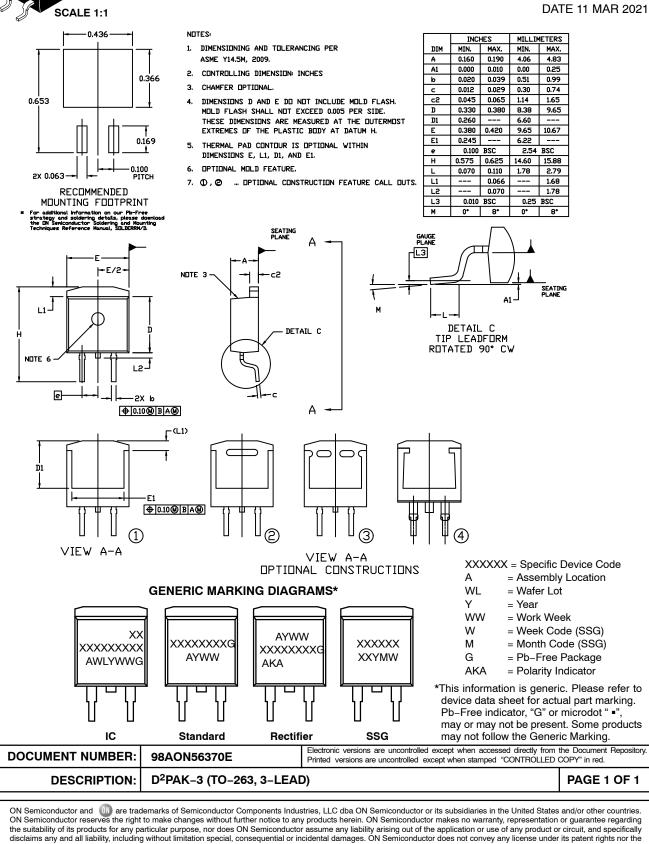
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#### MECHANICAL CASE OUTLINE PACKAGE DIMENSIONS

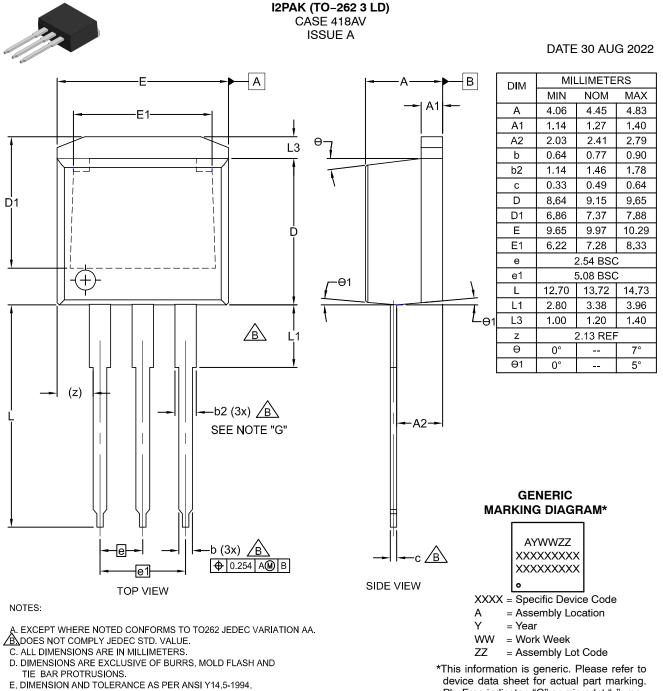






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- F. LOCATION OF PIN HOLE MAY VARY (LOWER LEFT CORNER,
- LOWER CENTER AND CENTER OF PACKAGE)
- G. MAXIMUM WIDTH FOR F102 DEVICE = 1.35 MAX.

device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "•", may or may not be present. Some products may not follow the Generic Marking.

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